

Centralized. Connected. Controlled.

i3070 Core Data Console



Turn Test Data into Immediate Root Cause Insights

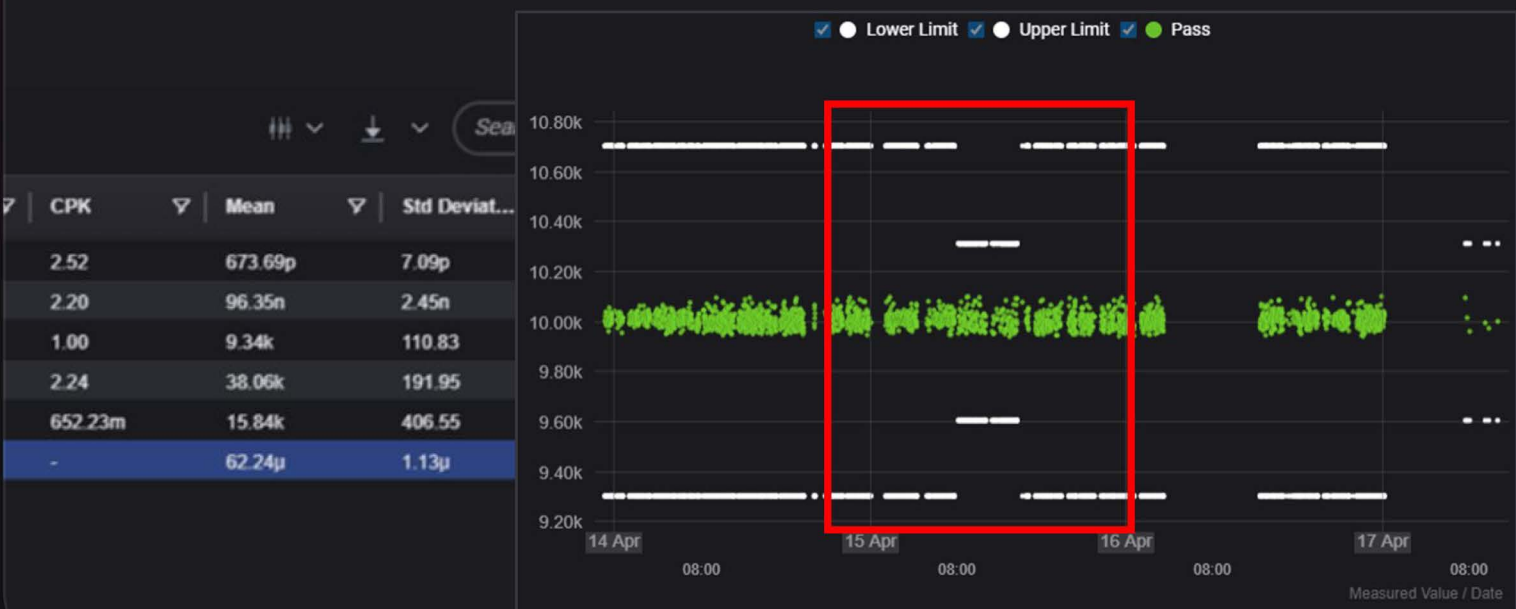
Stop Issues Before They Impact Production 1

Monitor yield and test performance in real time to catch issues early at the tester, and quickly identify top failing tests driving yield loss



Detect and Validate Test Limit Changes Instantly 2

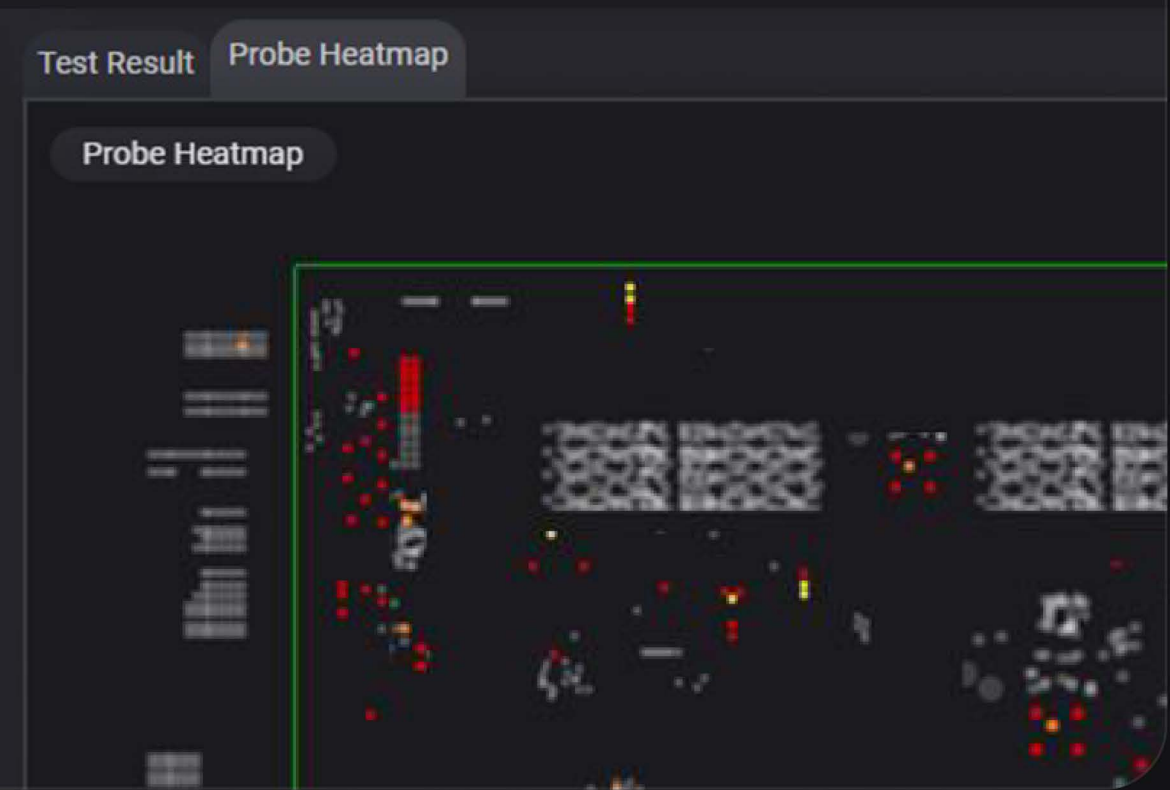
Spot trend shifts, compare limits over time, and identify inconsistencies in CPK to detect abnormal changes instantly.



Pinpoint Issues at the Exact Probe Location 3

Analyze failures and correlate test data directly at the tester to quickly identify root causes.

- Quickly determine if failures are caused by:
- Probe contact issues
 - Fixtures
 - Component defects



Compare Panels to Identify Hardware-Related Issues 4

Differences between panels immediately highlight hardware-related issues without manual investigation.

